



Features

- ▶ compact design saves board space
- ▶ RoHS compliant and lead-free
- ▶ Halogen-free
- ▶ Fast reponse to flault current
- **▶** Symmetrical design

Applications

- ▶ USB port protection USB 2.0, 3.0&OTG
- ► HDMI 1.4 Source protection
- ▶ PDAs / digital cameras
- ▶ Game console port protection
- ▶ PC motherboards-plug and play protection

HF RoHS REACH Pb Free

1.Electrical Characteristics

	I-hold I-trip	V/may Im	lmay	Incarr Del trus	Max. Time to trip		R0 min	R1max	
Model	I-HOIG	i-trip	I-trip Vmax Imax Pd		Pd typ	Current	Time	KU IIIIII	TTIIIAX
	(A)	(A)	(Vdc)	(A)	(W)	(A)	(Sec.)	(Ohm)	(Ohm)
SMD0603P004TF	0.04	0.12	24.00	20.00	0.50	0.20	1.00	4.00	40.00
SMD0603P010TF	0.10	0.30	15.00	40.00	0.50	0.50	1.00	0.90	6.00
SMD0603P020TF	0.20	0.50	9.00	40.00	0.50	1.00	0.60	0.55	3.50
SMD0603P025TF	0.25	0.50	9.00	40.00	0.50	1.00	0.60	0.50	3.00
SMD0603P035TF	0.35	0.70	6.00	40.00	0.50	8.00	0.10	0.20	1.40
SMD0603P050TF	0.50	1.00	6.00	40.00	0.50	8.00	0.10	0.10	0.80

I-hold: Holding Current: maximum current at which the device will not trip in 25°C still air.

I-trip: Tripping Current: minimum current at which the device will trip in 25°C still air.

Vmax: Maximum voltage device can withstand without damage at rated current(Imax).

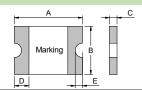
I max: Maximum fault current device can withstand without damage at rated voltage(Vmax).

Pd typ:Typical power dissipated from device when in the tripped state at 25°C still air.

R0 min:Minimum resistance of device in initial (un-soldered) state.

R1 max:Maximum resistance of device at 25°C measured one hour after tripping or reflow soldering of 260°C for 20 sec.

2.Product Dimensions(mm)&Marking



Model	A B		3	С		D		Е	Morking	
	Min	Max	Min	Max	Min	Max	Min	Max	Min	Marking
SMD0603P004TF	1.45	1.85	0.65	1.05	0.40	0.80	0.15	0.50	0.05	С
SMD0603P010TF	1.45	1.85	0.65	1.05	0.40	0.80	0.15	0.50	0.05	1
SMD0603P020TF	1.45	1.85	0.65	1.05	0.40	0.80	0.15	0.50	0.05	2
SMD0603P025TF	1.45	1.85	0.65	1.05	0.40	0.80	0.15	0.50	0.05	2
SMD0603P035TF	1.45	1.85	0.65	1.05	0.40	0.80	0.15	0.50	0.05	3
SMD0603P050TF	1.45	1.85	0.65	1.05	0.60	1.00	0.15	0.50	0.05	5

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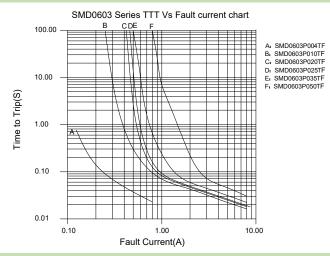


3. Thermal Derating Chart

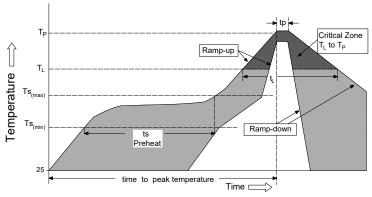
Recommended hold current(A) at ambient Temperature(°C)

Madal	Ambient Operating Temperature								
Model	-40°C	-20°C	0℃	25℃	40°C	50°C	60°C	70°C	85°C
SMD0603P004TF	0.050	0.048	0.044	0.040	0.033	0.030	0.025	0.020	0.012
SMD0603P010TF	0.13	0.12	0.11	0.10	0.08	0.07	0.06	0.05	0.03
SMD0603P020TF	0.27	0.25	0.23	0.20	0.17	0.14	0.12	0.10	0.07
SMD0603P025TF	0.32	0.29	0.27	0.25	0.21	0.18	0.16	0.14	0.10
SMD0603P035TF	0.47	0.41	0.38	0.35	0.29	0.26	0.24	0.20	0.14
SMD0603P050TF	0.67	0.59	0.54	0.50	0.41	0.37	0.34	0.29	0.20

4. Typical time to trip at 25°C



5. Soldering parameters



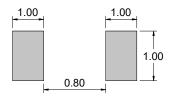
Profile Feature	Pb-Free Assembly	
Average Ramp-Up	3°C/second max	
	Temperature Min (Ts _(min))	150°C
Pre Heat:	Temperature Max (Ts _(max))	200°C
	Time (Min to Max) (t _s)	60 – 180 secs
Time Maintained	Temperature (T∟)	217°C
Above:	Temperature (t _L)	60 – 150 seconds
Peak / Classificati	260 ^{+0/-5} °C	
Time within 5°C of	20 – 40 seconds	
Ramp-down Rate	6°C/second max	
Time 25°C to peal	8 minutes Max.	

- ◆All temperature refer to topside of thepackage, measured on the package body surface
- ◆If reflow temperature exceeds the recommended profile, devices may not meet the performance requirements
- ◆Recommended reflow methods: IR,vapor phase oven,hot air oven,N2 environment for lead
- ◆Recommended maximum paste thickness is 0.25mm (0.010inch)
- ◆Devices can be cleaned using standard industry methods and solvents

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6.Recommended Pad Layout(mm) & Physical Specifications



Terminal Material	Tin-Plated Nickle-Copper (Solder Material:		
reminal Material	Matte Tin (Sn))		
Lood Coldorability	Meets EIA Specification RS186-9E,		
Lead Solderability	ANSI/J-STD-002 Category 3.		

7. Environmental Specifications

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Operating Temperature	-40 °C to +85 °C		
Maximum Device Surface Temperature in Tripped State	125°C		
Passive Aging	+85 °C, 1000 hours ; ±5 % typical resistance change		
Humidity Aging	+85 °C, 85 % R.H. 1000 hours; ±5 % typical resistance change		
Thermal Shock	MIL-STD-202, Method 107;		
Thermal Shock	+85 °C to -40 °C, 20 times;-30 % typical resistance change		
Solvent Resistance	MIL-STD-202, Method 215 ; No change		
Vibration	MIL-STD-883, Method 2007, Condition A; No change		
Moisture Sensivity Level	Level 1, J-STD-020		
Storage Conditions	+40 °C Max. 70% RH Max. Packed in original packaging.		

8.Test Procedures And Requirements

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No.	Test	Test Conditions	Accept/Reject Criteria			
1	R0 min	Resistance measurement at 25°C	R0min ≤ R ≤ R1max			
2	R1 max	Resistance measurement one hour after post trip	R0min ≤ R ≤ R1max			
3	l-hold	Hold rated current 1800 second without trip, @ 25°C	No trip			
4	I-trip	Device must trip within 900 second under rated current, @25°C	Trip			
5	Max. time to trip	At specified current, 25 °C	T ≤ max. time to trip (seconds)			
6	Trip Cycle Life	Vmax, Imax, 100 cycles	No arcing or burning			
7	Trip Endurance	Vmax,Imax 24 hours	No arcing or burning			
8	Solderability	ANSI/J-STD-002	95 % min. coverage			

9. Tape and Reel Specifications & Packaging quantity per Reel

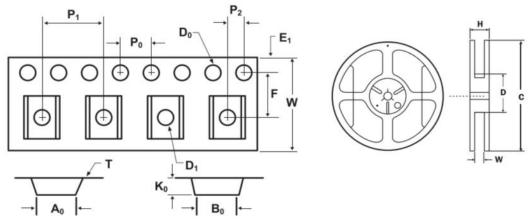
TAPE SPECIFICATIONS: EIA-481-1 (mm)				
Item	SMD0603P004TF SMD0603P010TF SMD0603P020TF SMD0603P025TF SMD0603P035TF	SMD0603P050TF		
W	8.00±0.30	8.00±0.30		
F	3.50±0.10	3.50±0.10		
E1	1.75±0.10	1.75±0.10		
D0	1.55±0.05	1.55±0.05		
D1	0.50±0.10	0.50±0.10		
P0	4.00±0.10	4.00±0.10		
P1	4.00±0.10	4.00±0.10		
P2	2.00±0.05	2.00±0.05		
A0	1.10±0.10	1.10±0.10		
B0	1.85±0.10	1.90±0.10		
Т	0.20±0.10	0.20±0.10		
K0	0.72±0.10	0.85±0.10		
Leader	390mm	390mm		

REEL DIMENSIONS: EIA-481-1 (mm)			
С	Ø178±1.0		
D	Ø60.2±0.5		
W	9.0±1.5		
Н	11.0±0.5		

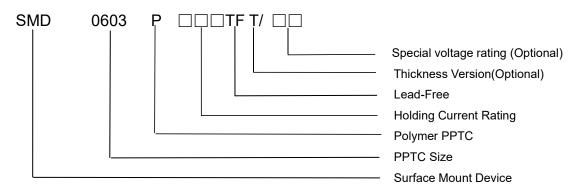
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10. Part Ordering Number System





- ■Users shall independently assess the suitability of these devices for each of their applications
- Operation of these devices beyond the stated maximum ratings could result in damage to the devices and lead to electrical arcing and/or fire
- These devices are intended to protect against the effects of temporary over-current or over-temperature conditions and are not intended to perform as protective devices where such conditions are expected to be repetitive or prolonged in duration
- Exposure to silicon-based oils, solvents, electrolytes, acids, and similar materials can adversely affect the performance of these PPTC devices
- These devices undergo thermal expansion under fault conditions, and thus shall be provided with adequate space and be protected against mechanical stresses
- **☞** Circuits with inductance may generate a voltage (L di/dt) above the rated voltage of the PPTC device.

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